Se	earch	Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination
10/644,278	AHN, KIE
Examiner	Art Unit

SEARCHED				
Class	Subclass	Date	Examiner	
336	65, 83, 200, 206- 208, 232	6/11/2005	TTN	
257	531	6/11/2005	TTN	
updated		10/18/05	TTN	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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